Electronic Supplementary Material (ESI) for Journal of Materials Chemistry C.

Supporting information

Structural Evolution of $SrLaAl_{1-x}(Zn_{0.5}Ti_{0.5})_xO_4$ Ceramics and Effects on Their Microwave Dielectric Properties

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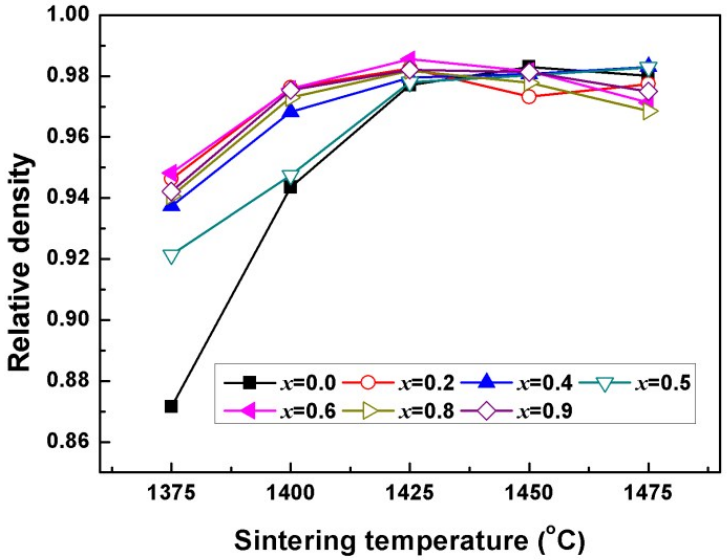
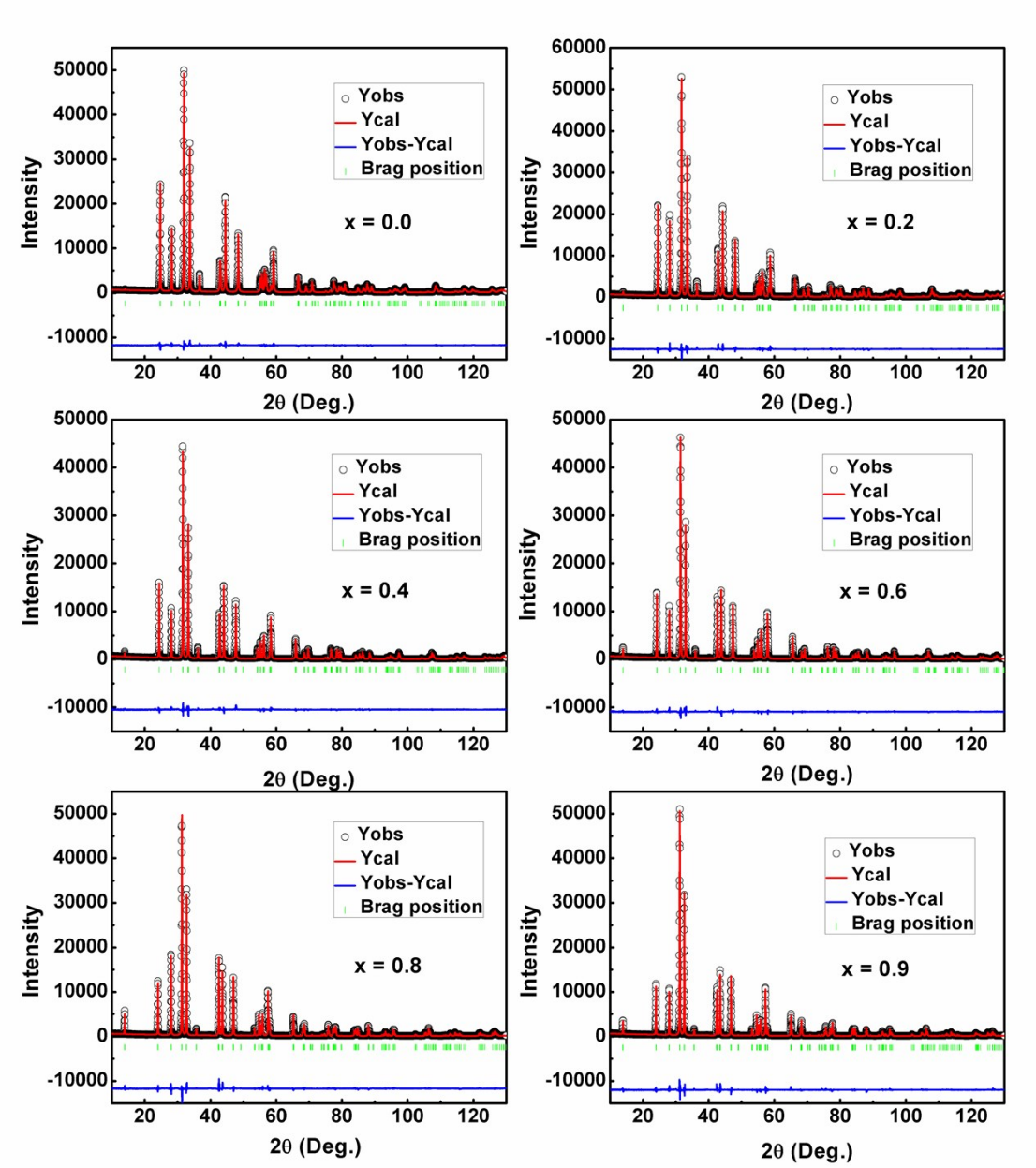
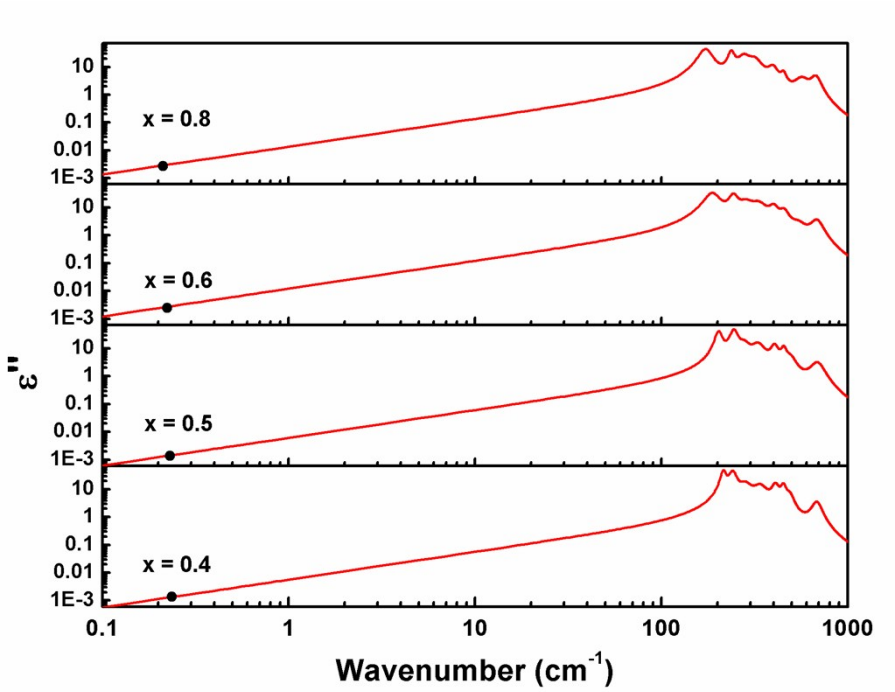


SI-Fig. 1 The relative density of $SrLaAl_{1-x}(Zn_{0.5}Ti_{0.5})_xO_4$ ceramics as a function of sintering temperature.



SI-Fig. 2 Experimental (circles) and calculated (red line) XRD profiles for the $SrLaAl_{1-x}(Zn_{0.5}Ti_{0.5})_xO_4$ samples. The short vertical lines below the patterns mark the positions of Bragg reflections. The bottom continuous line is the difference between the observed and the calculated intensity.



SI-Fig. 3 The imaginary parts of the complex dielectric responses (red lines) of $SrLaAl_{1-x}(Zn_{0.5}Ti_{0.5})_xO_4$ (x = 0.4, 0.5, 0.6, 0.8) ceramics. Black circles are the experimental data measured at microwave range.